

Search Notes

Application/Control No.

10/624,456

Examiner

LEE NGUYEN

Applicant(s)/Patent under
Reexamination

KERTH ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	296 300 301	4/26/2006	LN
	106		
330	170	4/26/2006	LN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPG-PUB; USPAT; EPO; JPO; DERWENT) SEE SEARCH HISTORY	4/26/2006	LN